


<b>Search Notes</b>  	<b>Application/Control No.</b>  10510372	<b>Applicant(s)/Patent Under Reexamination</b>  STRAUB ET AL.
	<b>Examiner</b>  Izunna Okeke	<b>Art Unit</b>  2432

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Updated Classification Search + Keyword Search (See History)	3/24/2009	IO
Updated Text Search (See History)	3/24/2009	IO
Classification Search (380/255, 455/418, 455/420, 455/466, 455/419, 713/168, 713/169, 340/310) (See History)	3/24/2009	IO
NPL Search (IEEE documents)	3/24/2009	IO

INTERFERENCE SEARCH			
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